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Design of Survey X-Ray Spectrometer for NIF, NSS

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Design of Survey X-Ray Spectrometer for NIF, “NSS”

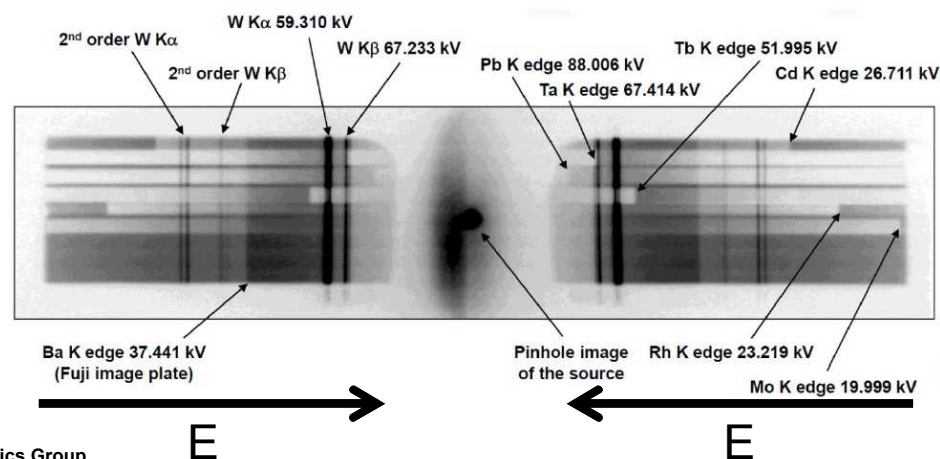
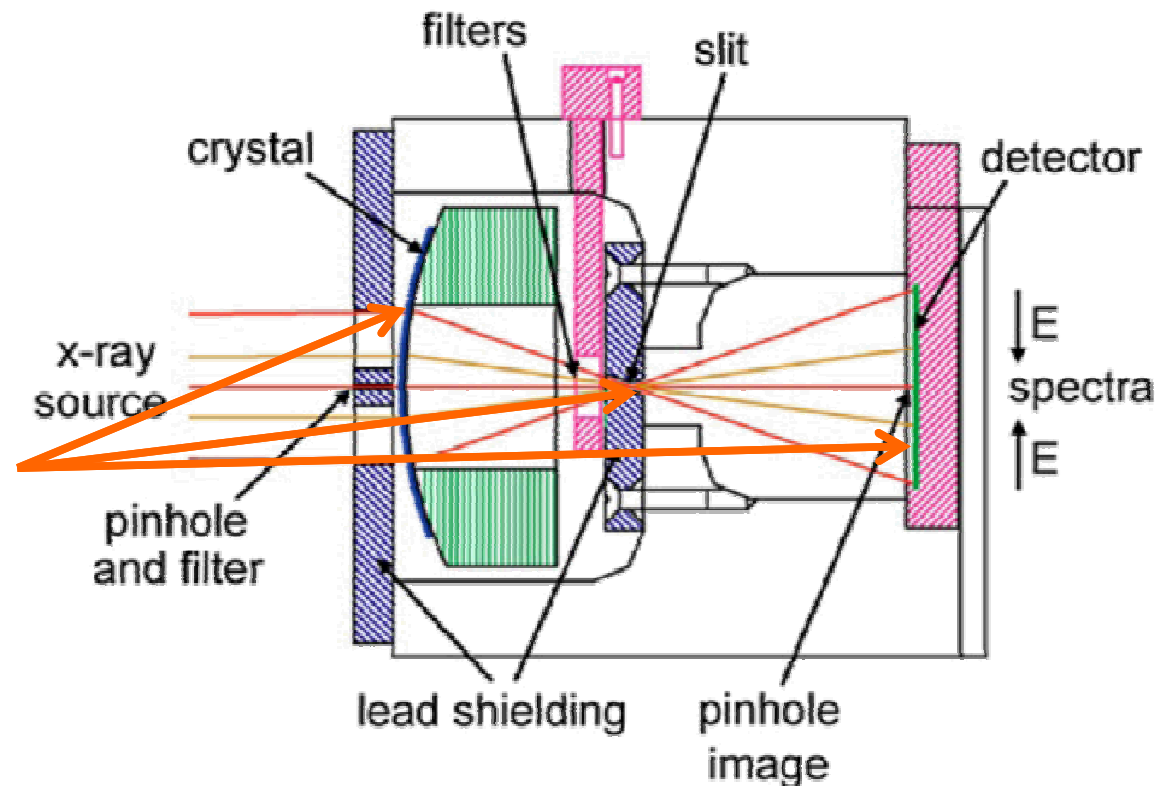
Shannon Ayers, Perry Bell, Dave Bradley, Uri Feldman,
Walter Marlin, Marilyn Schneider, John Seely
8/28/13

X-Ray Spectrometer Overview

- **X-Ray Spectrometers have been successfully deployed, at many facilities including OMEGA and NIF, to study emission and absorption spectra of materials.**
- **Function: High resolution spectra covering the 6 – 365 keV in a single shot**
 - **NIF is currently limited to 5.8 – 16.5 keV**
- **High energy density source development applications**
 - **Complimentary instrument on NIF is FFLEX**
- **The NSS design is based on spectrometers successfully deployed at LLE on the OMEGA and EP lasers.**
 - **Cauchois Type Spectrometer**
 - **Two identical channels**
 - **Cylindrically bent transmission crystals**

Cauchy Type Spectrometer Design

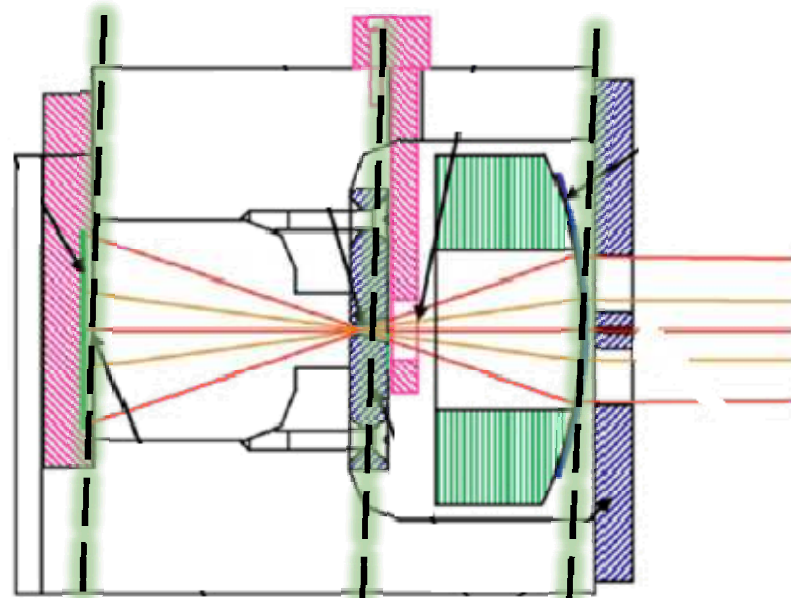
- All X-Rays of a given energy, from an extended source, are focused on the Rowland circle
- Spectrometer consists of
 - Cylindrically bent transmission crystals
 - Slit Aperture
 - Detector placed on the Rowland Circle
- Rays diverging from the source are diffracted by the crystal and pass through the slit to the detector, producing two spectra that are symmetric about the axis



Implementation on NIF

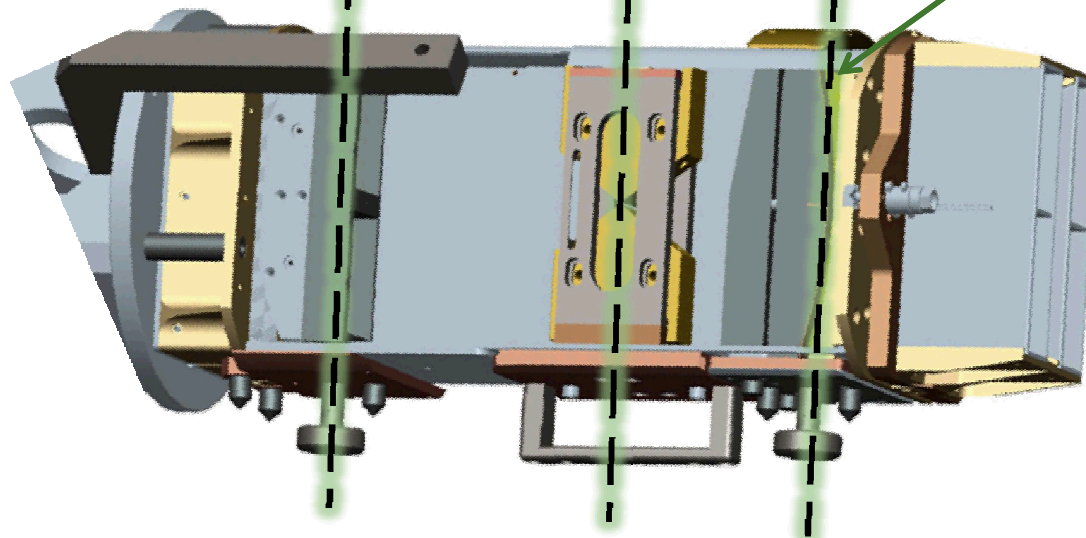
Effects of Penetrating Radiation Neutrons

- No line of sight from source to detector
- Shielding in front of crystal
- Shielding at the slit



Larger Source to crystal standoff distance

- Longer crystals necessary to achieve wide range of Bragg angles and energy coverage
- Unique alignment hardware / plan



Implementation on NIF, cont.

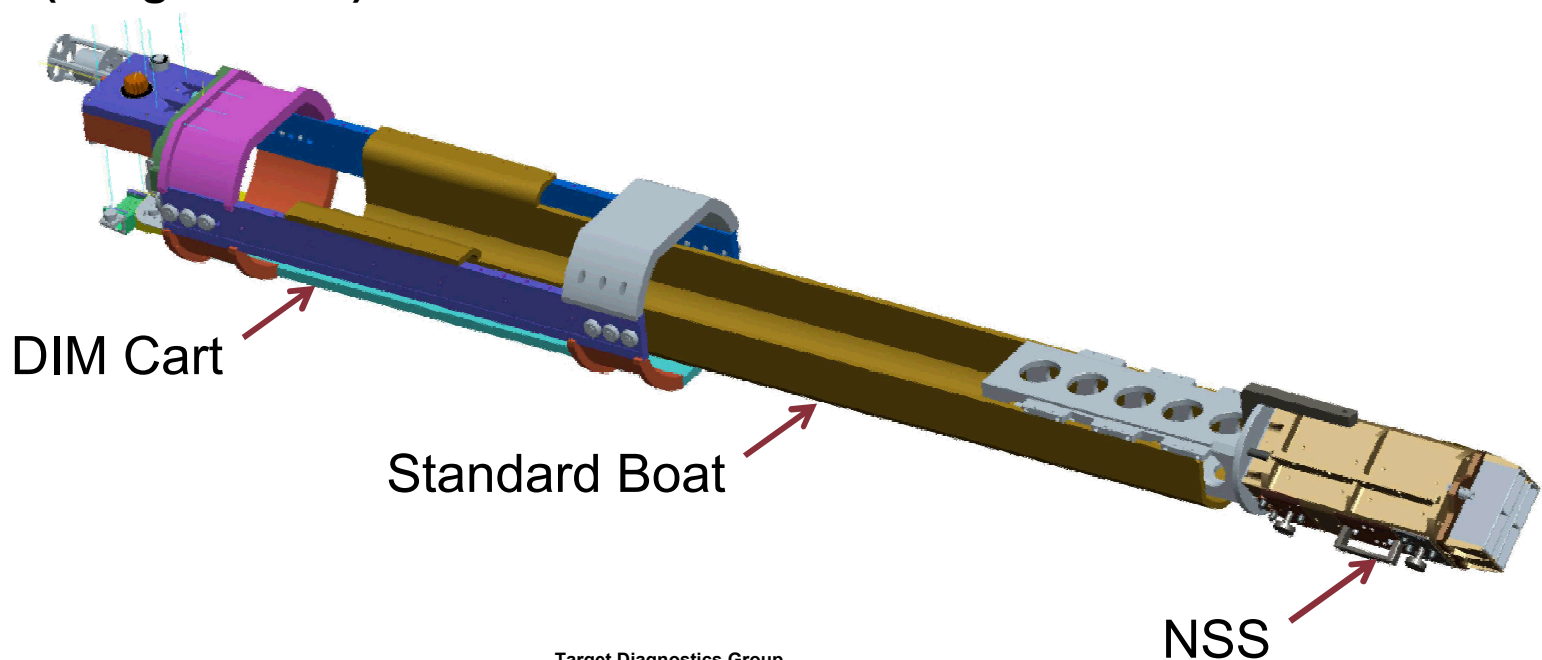
Phased Approach to Implementation on NIF

Phase A Diagnostic Instrument Manipulator
(DIM) Based Instrument

Phase B Custom Manipulator on NIF

NSS on NIF

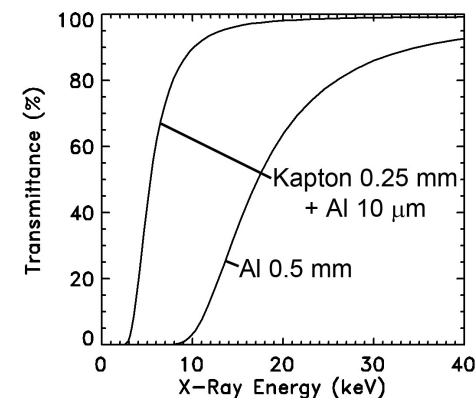
- **NSS Function:**
 - High resolution spectra covering the x-ray/gamma-ray range 6-365 keV
- **NSS Features:**
 - DIM (Diagnostic Instrument Manipulator) and TIM (Ten Inch Manipulator) compatible, 3 m standoff distance from TCC (Target Chamber Center).
 - Two spectrometer channels with identical geometry and interchangeable crystals.
 - Five interchangeable crystals cover 6 – 365 keV in 1st order with >200 resolving power, 511 keV in 2nd order.
 - IPs (Image Plates) for Data Collection



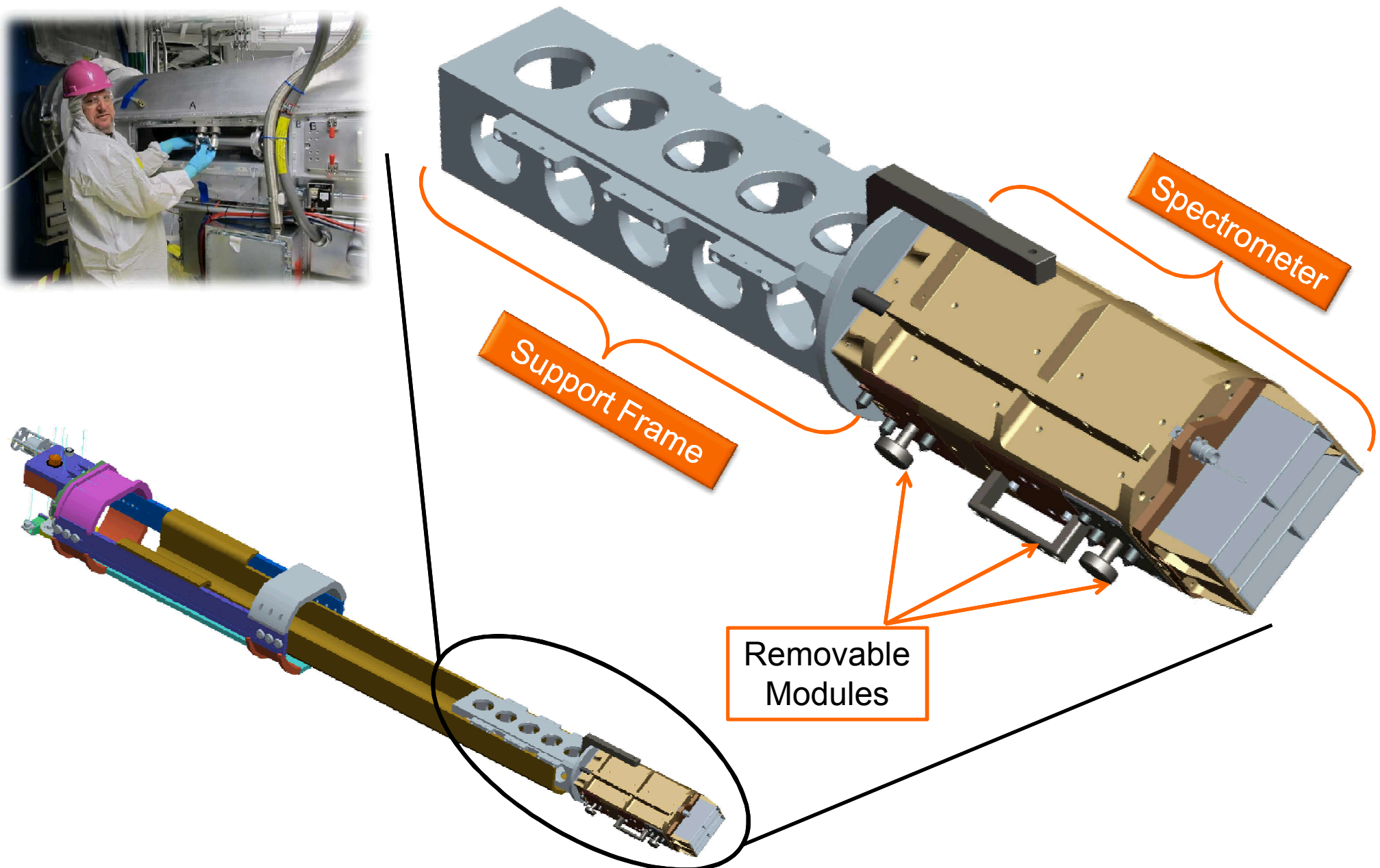
NSS Crystals: Discrete Energy Ranges and K Edge Filters

NSS crystal type	#1	#2	#3	#4	#5
Quartz diffracting planes	(100)	(101)	(203)	(502)	(550)
Number provided	6	5	4	4	4
Lattice spacing 2d (nm)	0.8512	0.6684	0.2750	0.1624	0.0983
Energy coverage (keV)	6 - 49	8 - 63	19 - 152	32 - 260	53 - 400
Crystal thickness (mm)	0.08-0.10	0.08-0.10	0.25	0.25	0.50
Relative diffraction efficiency	30	100	40	13	6
Perpendicular planes	(001)	(1-20)	(1-20)	(1-20)	(001)
Blast window material	Kapton/Al	Kapton/Al	Al	Al	Al
Blast window thickness	0.25 mm/10 μ m	0.25 mm/10 μ m	0.5 mm	0.5 mm	0.5 mm
K edge filter materials	Mn, Mo	Cu, Ho	Ag, Au	Ho, Pb	Hf, U
Filter thicknesses (μ m)	10, 100	10, 100	100, 150	100, 150	100, 200
Filter K edge energies (keV)	6.538, 20.000	8.980, 55.620	25.516, 80.721	55.620, 88.006	65.316, 115.601
Image plate Ba K edge (keV)	37.452	37.452	37.452	37.452	

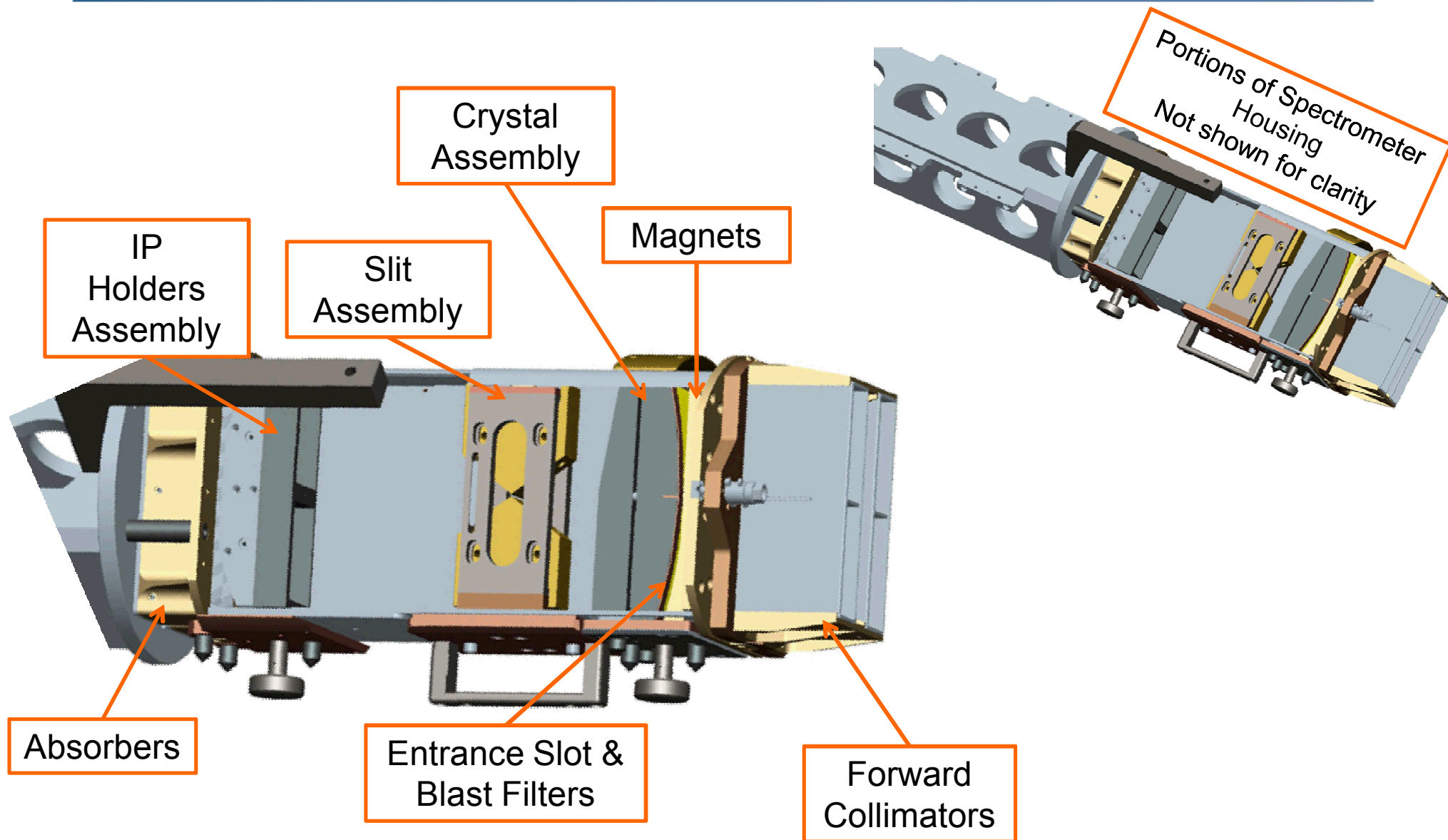
Thickness & Transmittance:
Blast Window size is 41.3 mm x 84.1 mm.



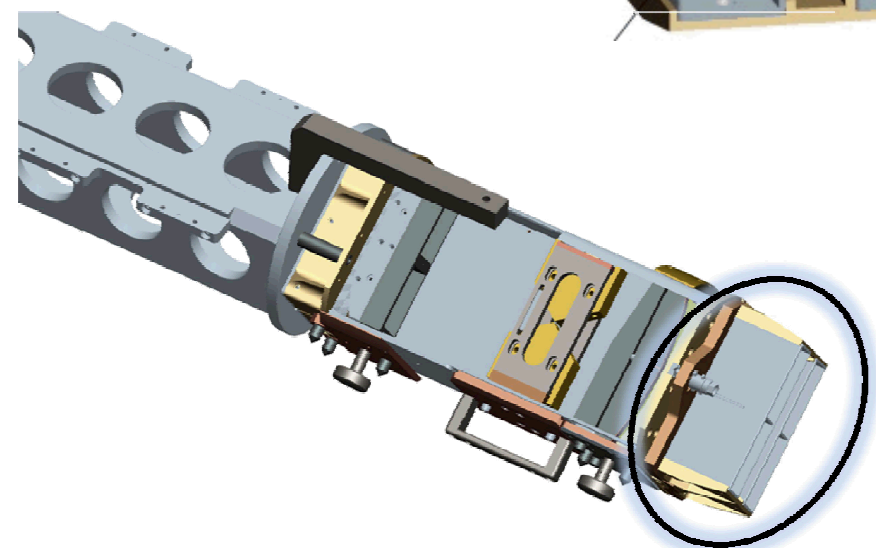
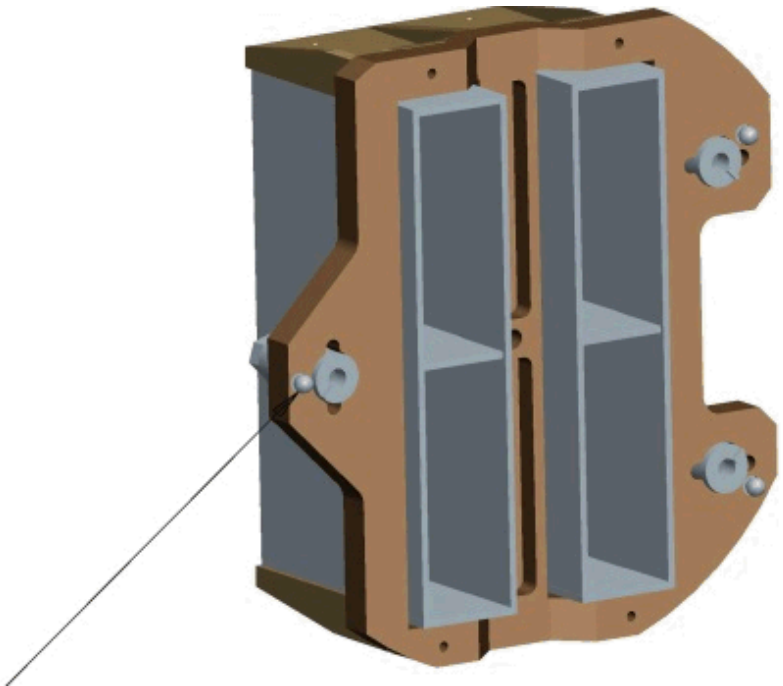
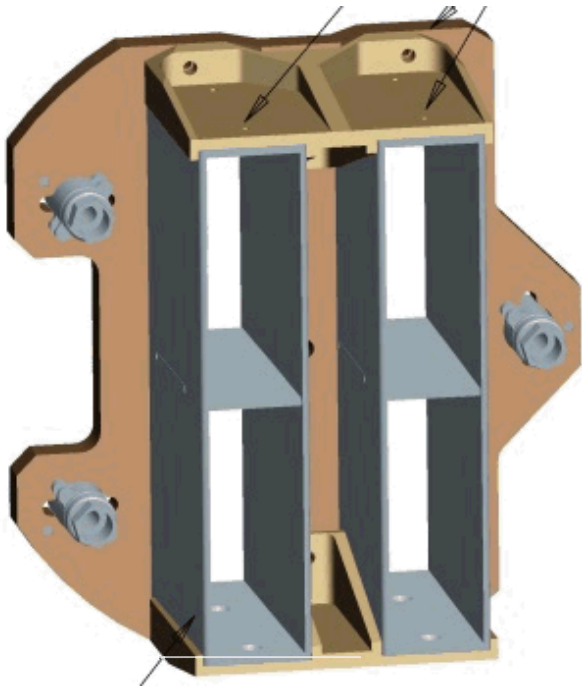
Overview of NSS Hardware



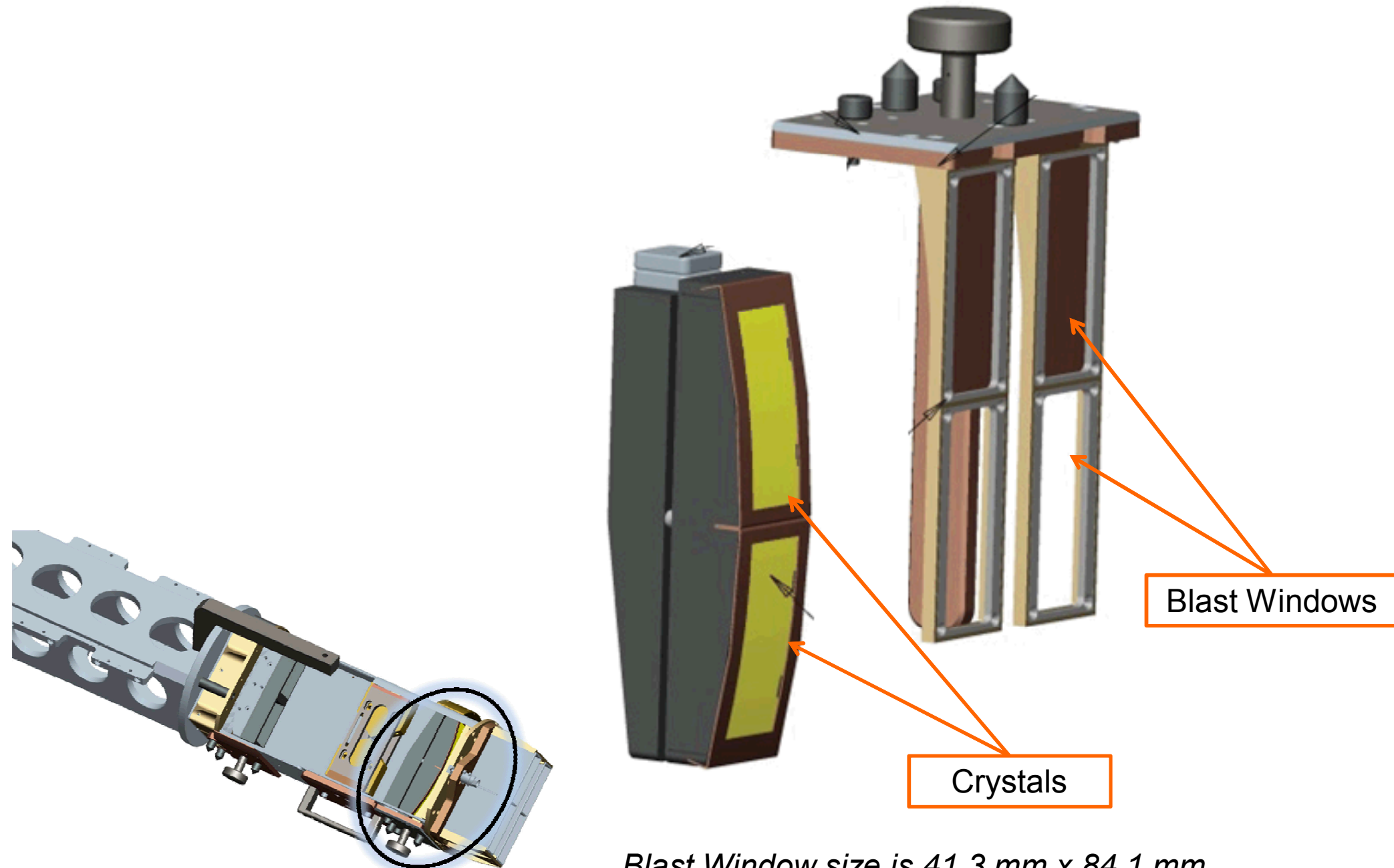
Overview of NSS Hardware, cont.



NSS Entrance Collimator Sub-Assembly

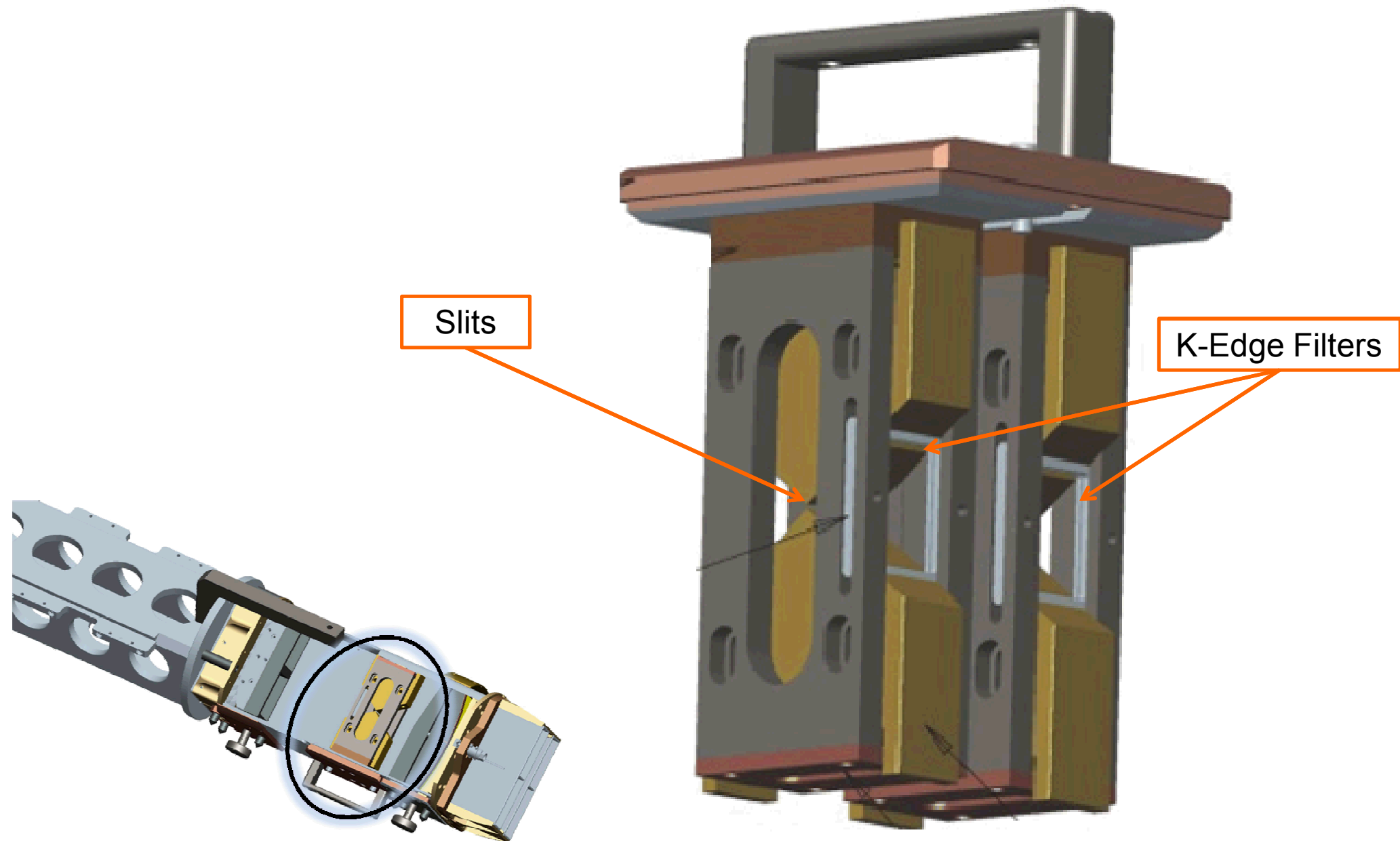


NSS Removable Crystal Module

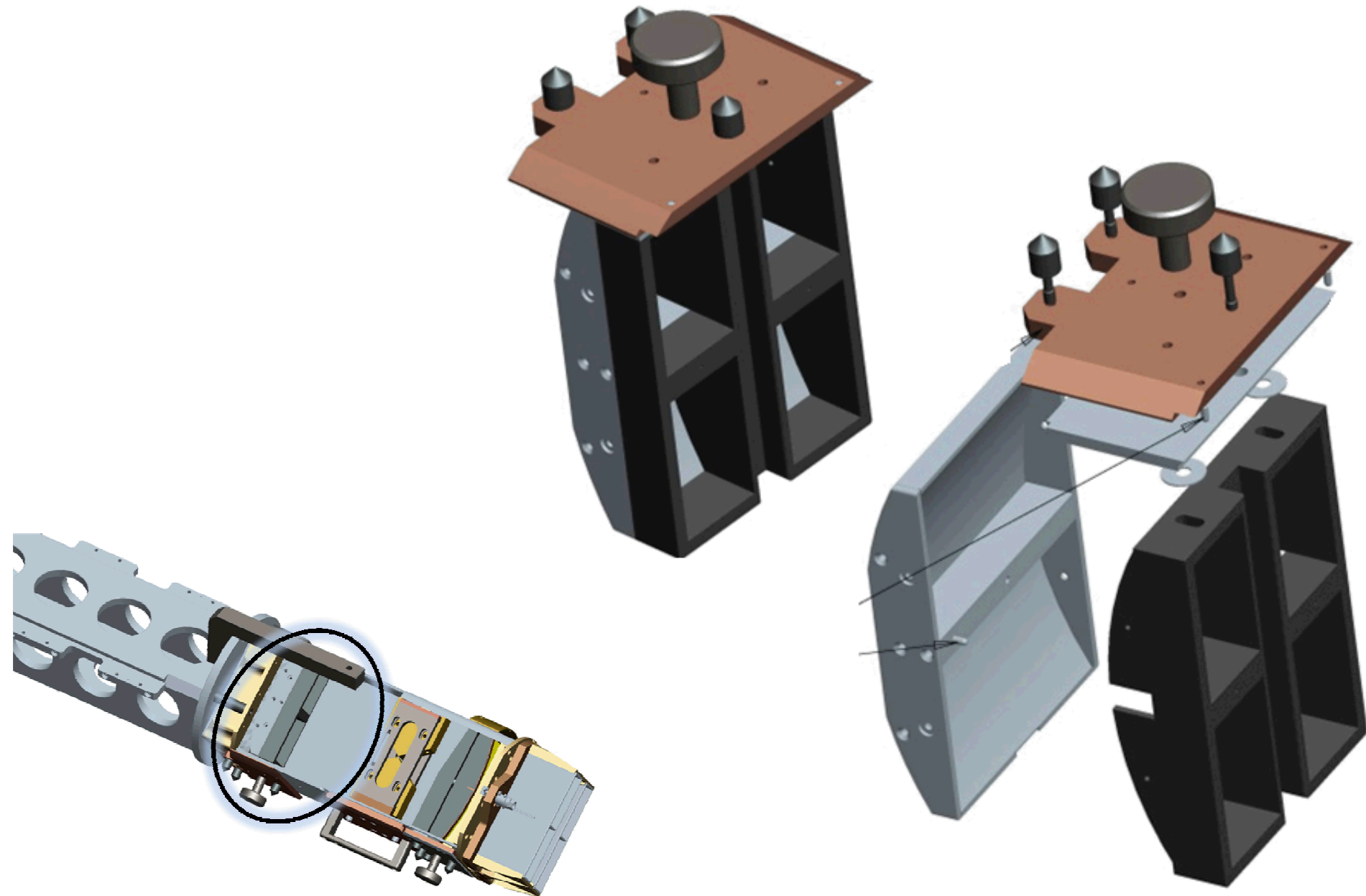


Blast Window size is 41.3 mm x 84.1 mm

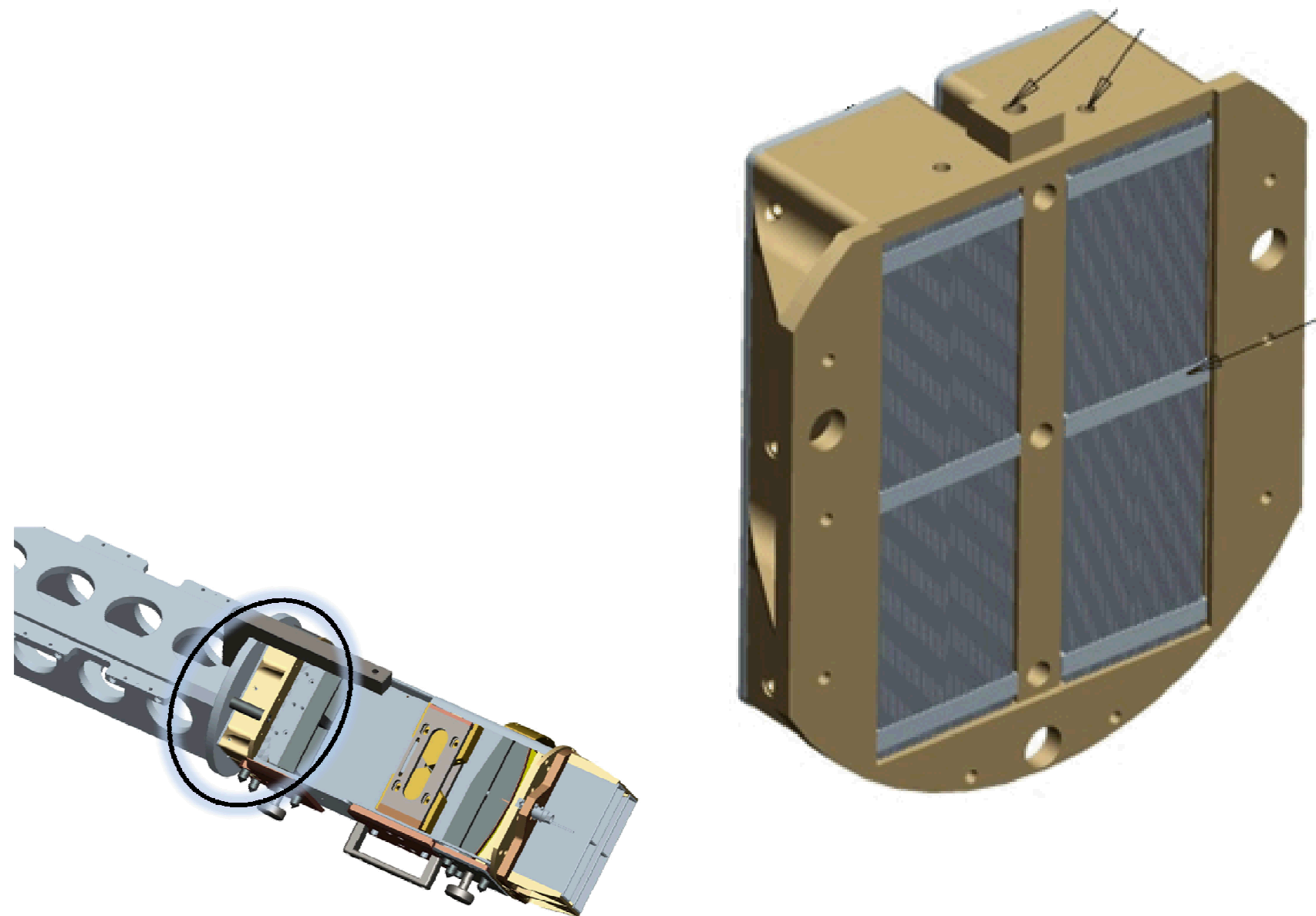
NSS Removable Crossover Slit Module



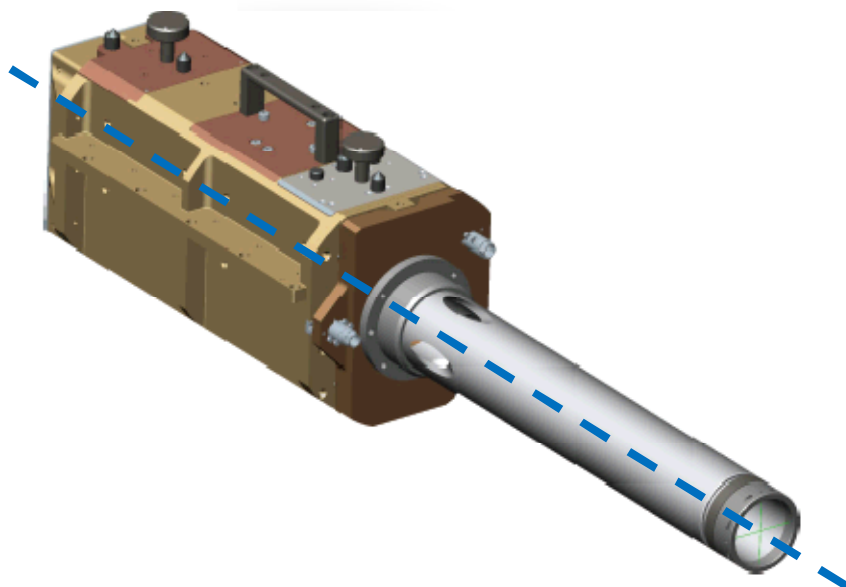
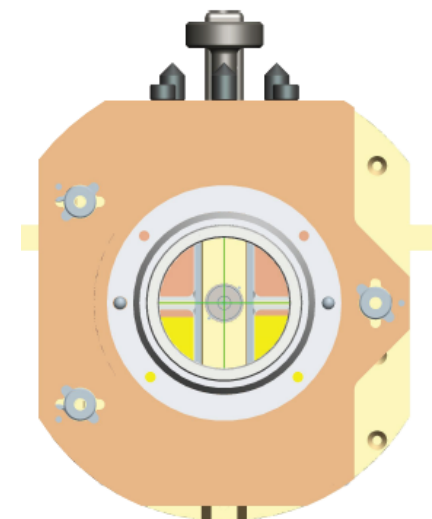
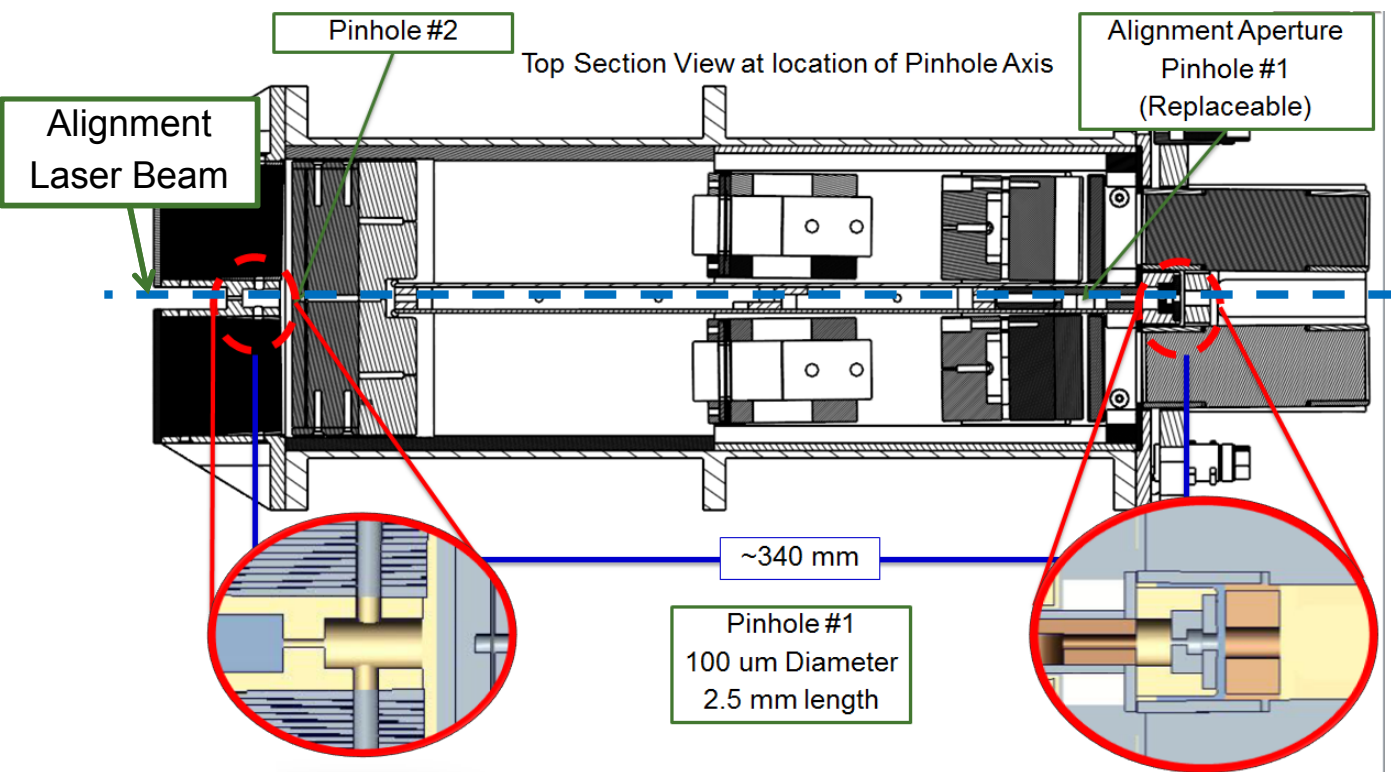
NSS Removable IP Module



NSS Absorber Sub-Assembly



NSS DIM Fixture & Alignment Fixture Assemblies



Alignment & Pointing	± 0.1 mm in X & Y at the slit 3000 mm (detector to TCC) stand-off ± 5 cm in Z
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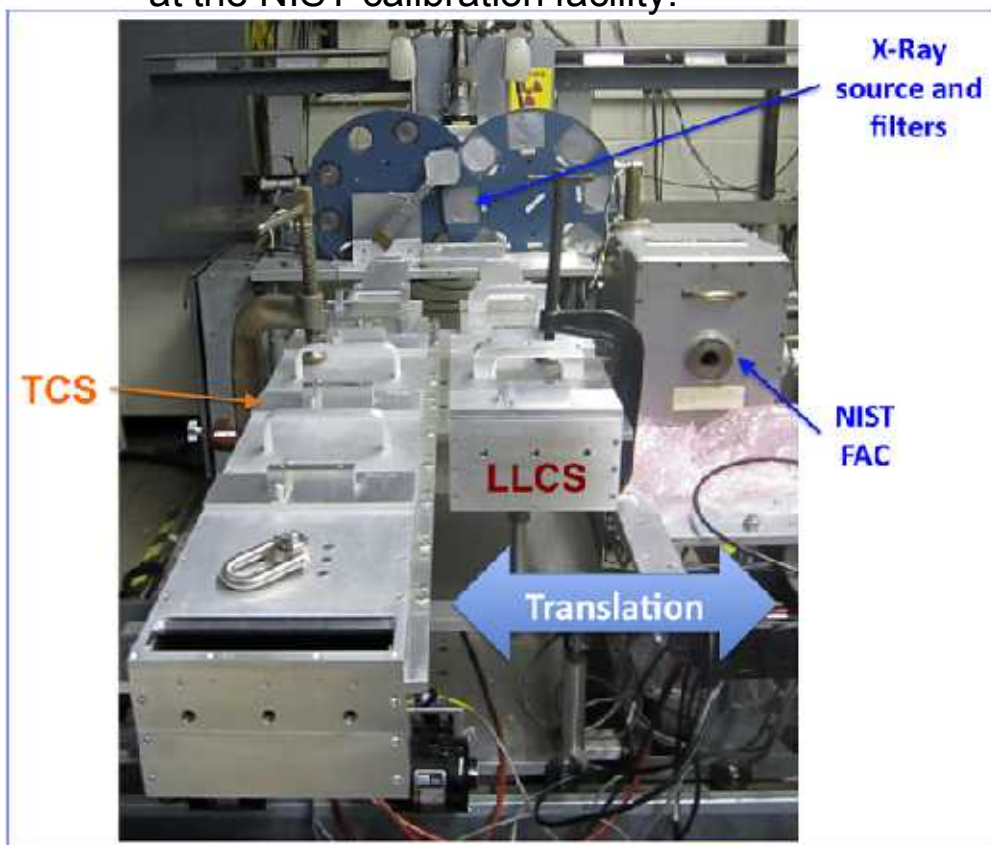
FOV	± 3 mm in X & Y (at TCC)
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Opposed Port Alignment System (OPAS) is used to align NSS

Calibration Plan

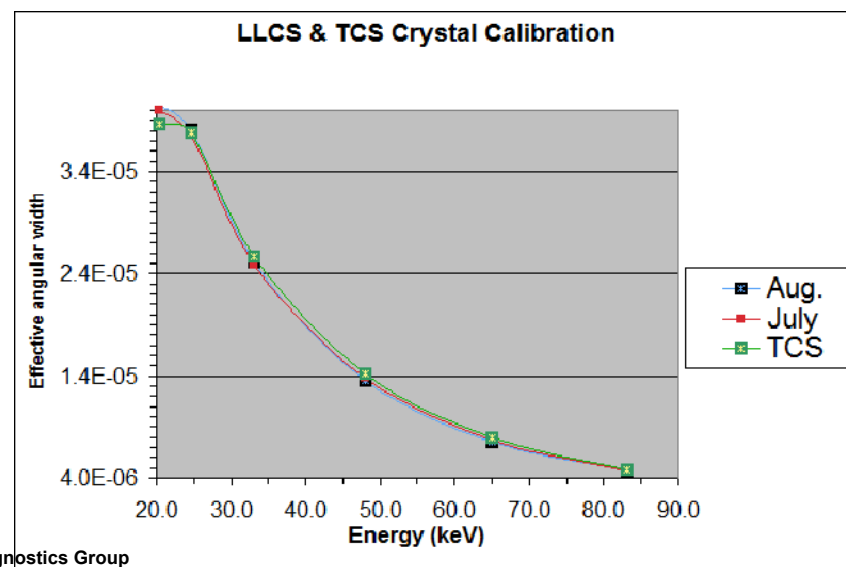
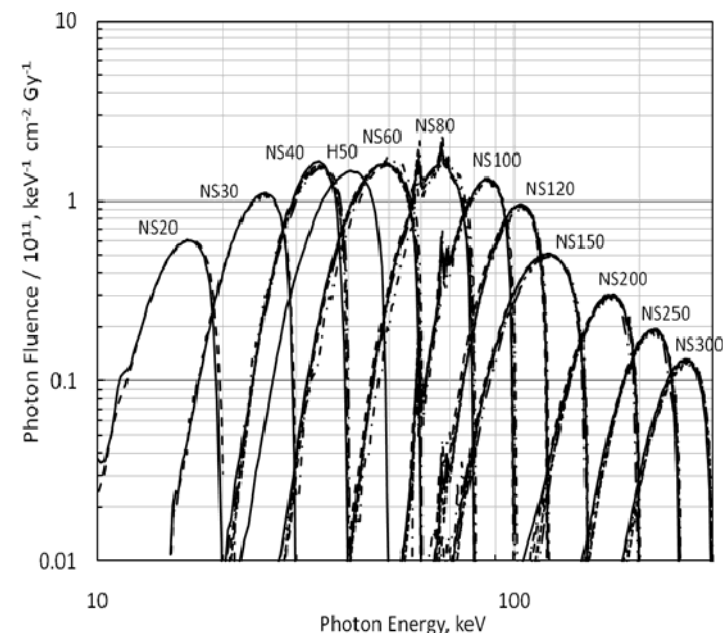
The NSS end-to-end sensitivity can be measured at the NIST calibration facility

Two spectrometers (TCS and LLCS) at the NIST calibration facility:







Calibration of the crystal integrated reflectivity:

Absolutely calibrated x-ray fluences:



NSS Project Status

	Phase		Description
Phase A	Phase I		Conceptual Design and Review
	Phase IIA		NSS and DIM/TIM Mounting Preliminary Design
	Phase IIB		Preliminary Design Details and Review
	Phase III		Final Design Details and Review
	Phase IV		Build Hardware
	Phase V		Calibration
Phase B	Phase VI		Custom Manipulator for NIF

- NSS will be ready for NIF shots 4th Quarter of FY14
- NSS is expected to meet the defined instruments requirements.
- NSS will add the ability to record a high resolution broad band spectrum

NIF

